ABSTRACT OF THE DISCLOSURE

A thickness measuring device for measuring the thickness dimension of an article being conveyed along a conveyor system comprises a rotary encoder, and a lever arm pivotally mounted upon the shaft of the rotary encoder. The lever arm has an end portion thereof disposed in contact with the article conveyor so as to be deflected by an article conveyed along the conveying path. Deflection of the lever arm causes the rotary shaft of the rotary encoder to undergo a predetermined amount of rotation which is indicative of the thickness dimension of the article being conveyed. The system is also operatively associated with a storage bin such that when a plurality of articles, having a predetermined cumulative thickness dimension, are detected, further conveyance of articles to the storage bin is terminated. The system further comprises a central processing unit (CPU) which has incorporated therein improved software which permits the system to accurately determine the thickness dimensions of articles having substantially constant, but relatively large thickness dimensions, as well as articles having variable dimensions.